

Kaleo MTF station

Product/Model: Spectral

Range UV (190 - 400 nm) VIS -

NIR (400 - 1100 nm) SWIR (900

- 1700 nm)



Product Introduction: The Kaleo MTF instrument is ideal for measuring sets of lenses at the design, prototyping, or production phase. It delivers the most complete lens characterization: on & off-axis MTF, radiometry, and wavefront error at multiple wavelengths. The Kaleo MTF measurement accuracy remains unchanged even at high CRA and FOV.

Key Features

- Compatible with large FOV (up to +/- 90°) and CRA (up to 50°) lenses
- Single shot MTF and WFE measurements
- On & off axis infinite to finite configuration

Applications

- Optics metrology and optical system alignment •

Specifications

MTF on-axis	Accuracy <1%* - Repeatability <0.5%*
MTF on-axis	Accuracy <2%* - Repeatability <1%*
MTF max frequency	1000 lp/mm
Distortion	Accuracy <0.5% - Repeatability <0.05%
OPD (on-axis)	Accuracy <20nm RMS - Repeatability <5nm RMS